

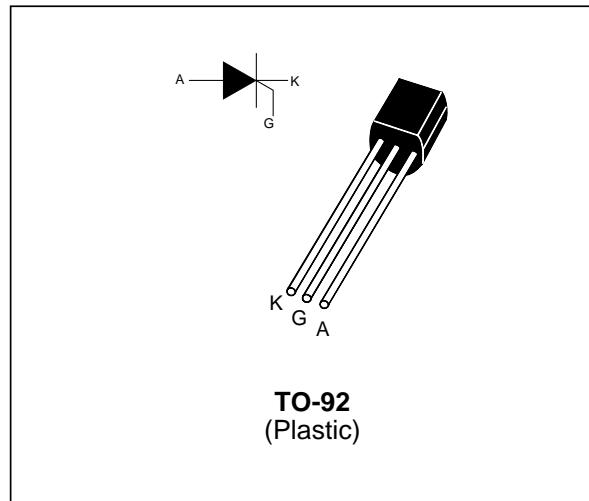
## SENSITIVE GATE SCR

### FEATURES

- $I_{T(RMS)} = 0.8A$
- Sensitive gate :  $I_{GT\ min} = 30\ \mu A$   
 $: I_{GT\ max} = 60\ \mu A$
- $V_{DRM}/V_{RRM} = 600\ V$
- Low holding current :  $I_H < 5\ mA$

### DESCRIPTION

The X00605MA SCR uses a high performance glass passivated PNPN technology. This device is perfectly suited for applications requiring very low gate sensitivity such as sensors, detectors, pilot for larger thyristors, Ground Fault Interruptor (GFI), small motor control, relay drivers, etc...



### ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit
$V_{DRM}$ $V_{RRM}$	Repetitive peak off-state voltage $R_{GK} = 1K\Omega$	$T_j = 125^\circ C$	600 V
$I_{T(RMS)}$	RMS on-state current ( $180^\circ$ conduction angle)	$T_l = 85^\circ C$	0.8 A
$I_{T(AV)}$	Average on-state current ( $180^\circ$ conduction angle)	$T_l = 85^\circ C$	0.5 A
$I_{TSM}$	Non repetitive surge peak on-state current ( $T_j$ initial = $25^\circ C$ )	$t_p = 8.3\ ms$	10 A
		$t_p = 10\ ms$	9
$I^2t$	$I^2t$ Value for fusing	$t_p = 10\ ms$	$A^2s$
$dI/dt$	Critical rate of rise of on-state current $I_G = 10\ mA$ $dI_G/dt = 0.1\ A/\mu s.$	50	$A/\mu s$
$T_{stg}$ $T_j$	Storage temperature range Operating junction temperature range	- 40, + 150 - 40, + 125	$^\circ C$
$T_l$	Maximum lead temperature for soldering during 10s at 2mm from case	260	$^\circ C$

## X00605MA

### THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R <sub>th(j-a)</sub>	Junction to ambient	150	°C/W
R <sub>th(j-l)</sub>	Junction to lead for DC	70	°C/W

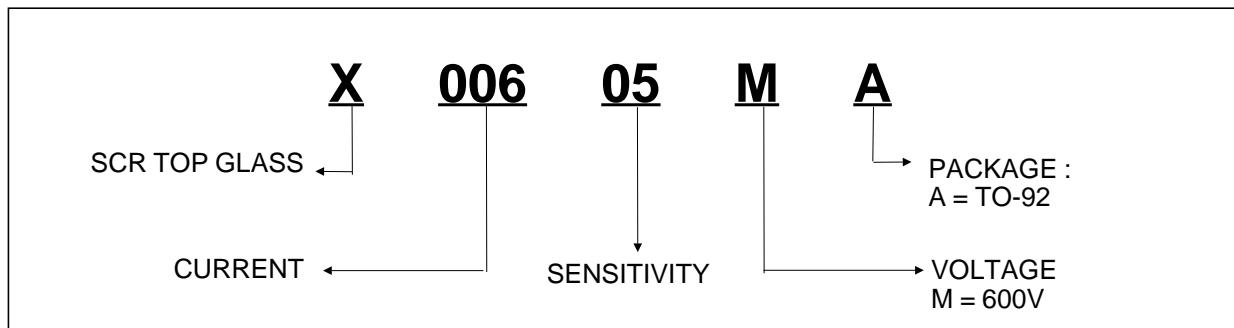
### GATE CHARACTERISTICS

P<sub>G (AV)</sub> = 0.1W    P<sub>GM</sub> = 2W (tp = 20μs)    I<sub>GM</sub> = 1A (tp = 20μs)

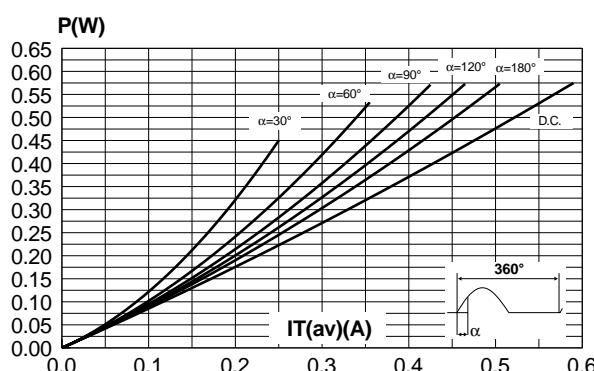
### ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions		Value	Unit
I <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MIN.	30
			MAX.	60
V <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MAX.	0.8
V <sub>GD</sub>	V <sub>D</sub> = V <sub>DRM</sub> R <sub>L</sub> = 33KΩ R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	MIN.	0.2
V <sub>RG</sub>	I <sub>RG</sub> = 10μA	T <sub>j</sub> = 25°C	MIN.	5
I <sub>H</sub>	I <sub>T</sub> = 50mA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX.	5
I <sub>L</sub>	I <sub>G</sub> = 500μA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX.	6
V <sub>TM</sub>	I <sub>TM</sub> = 1A tp= 380μs	T <sub>j</sub> = 25°C	MAX.	1.35
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>D</sub> = V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ V <sub>R</sub> = V <sub>RRM</sub>	T <sub>j</sub> = 25°C	MAX.	1
		T <sub>j</sub> = 125°C	MAX.	100
dV/dt	V <sub>D</sub> = 67%V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	MIN.	25
				V/μs

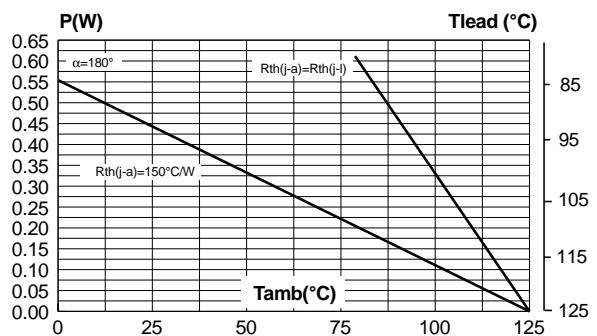
### ORDERING INFORMATION



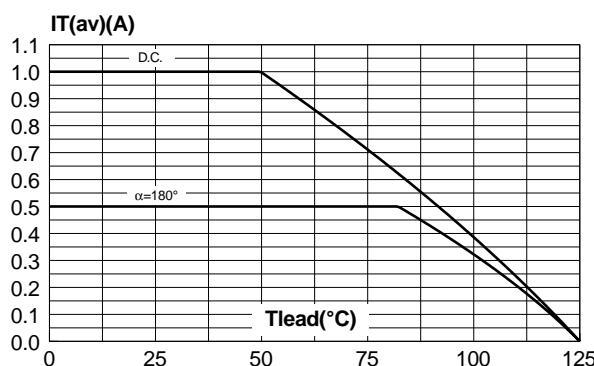
**Fig. 1:** Maximum average power dissipation versus average on-state current.



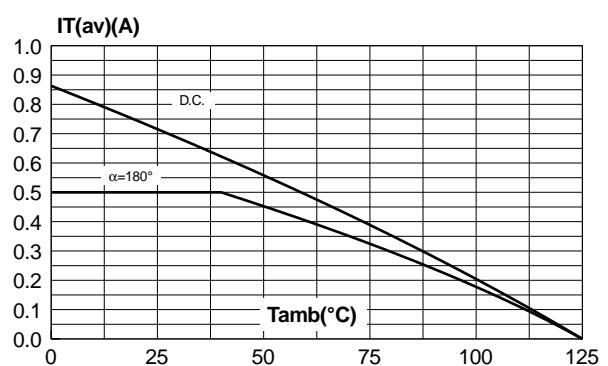
**Fig. 2:** Correlation between maximum average power dissipation and maximum allowable temperature (Tamb and Tlead).



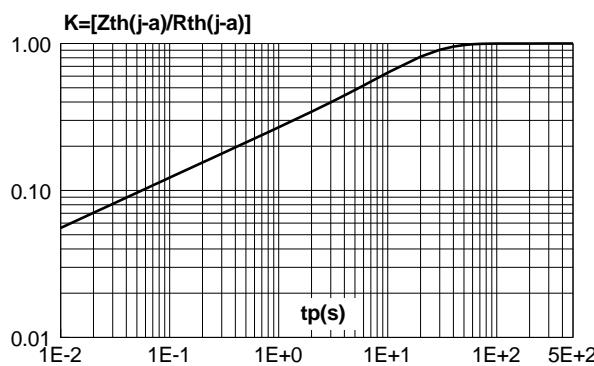
**Fig. 3-1:** Average and D.C on-state current versus lead temperature.



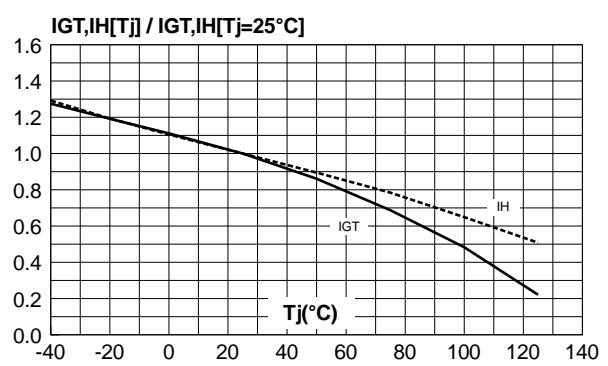
**Fig. 3-2:** Average and D.C on-state current versus ambient temperature (device mounted on FR4 with recommended pad layout).



**Fig. 4:** Relative variation of thermal impedance junction to ambient versus pulse duration.

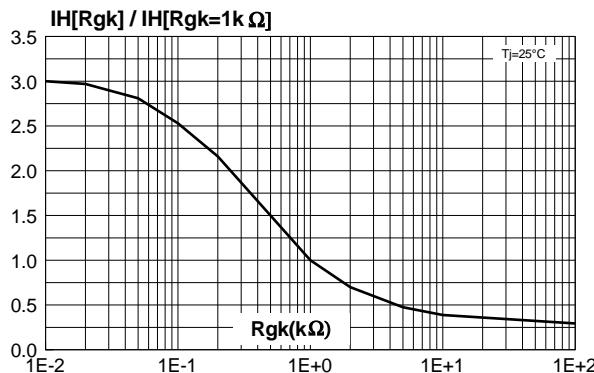


**Fig. 5:** Relative variation of gate trigger current and holding current versus junction temperature.

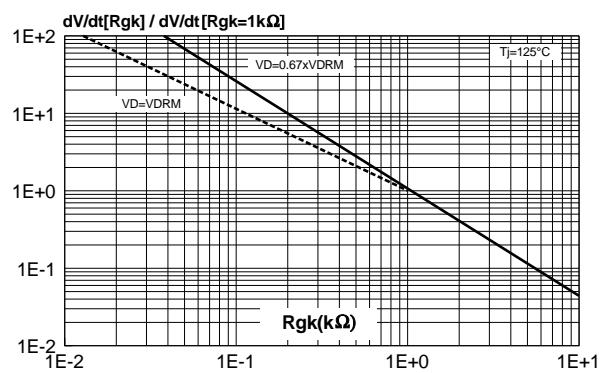


## X00605MA

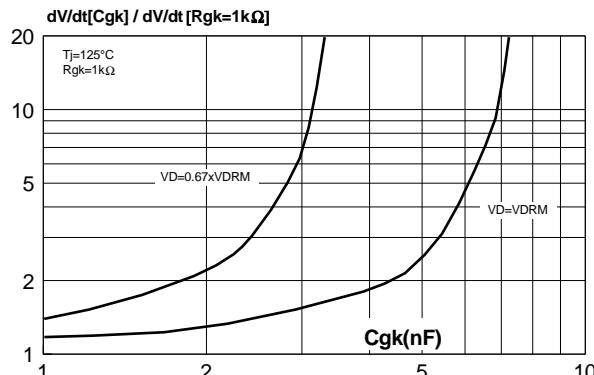
**Fig. 6:** Relative variation of holding current versus gate-cathode resistance (typical values).



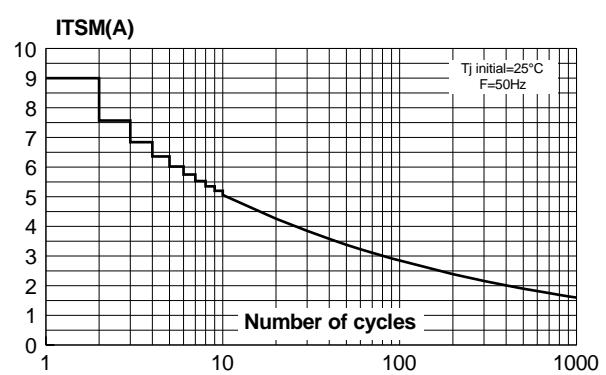
**Fig. 7:** Relative variation of dV/dt immunity versus gate-cathode resistance (typical values).



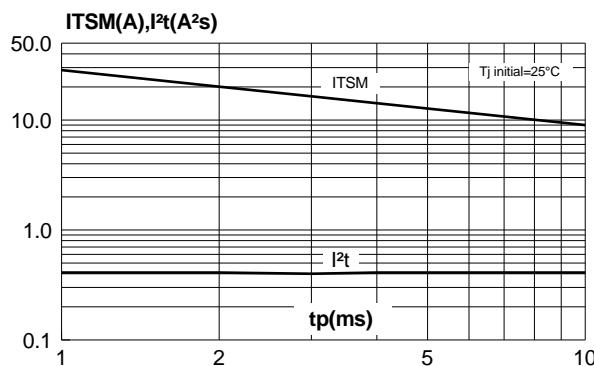
**Fig. 8:** Relative variation of dV/dt immunity versus additional gate-cathode capacitance (typical values).



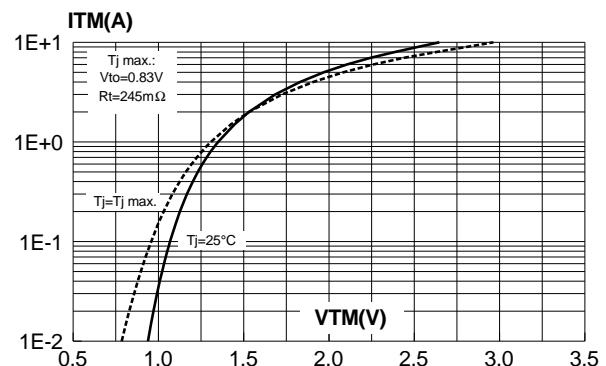
**Fig. 9:** Non repetitive surge peak on-state current versus number of cycles.



**Fig. 10:** Non repetitive surge peak on-state current for a sinusoidal pulse with width :  $t_p = 10\text{ms}$ , and corresponding value of  $I^2t$ .

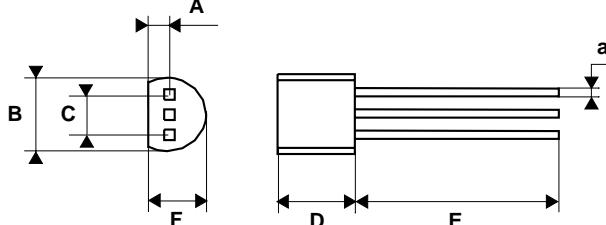


**Fig. 11:** On-state characteristics (maximum values).



**PACKAGE MECHANICAL DATA**  
TO-92 (Plastic)

REF.	DIMENSIONS					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A		1.35			0.053	
B			4.70			0.185
C		2.54			0.100	
D	4.40			0.173		
E	12.70			0.500		
F			3.70			0.146
a			0.45			0.017



Ordering type	Marking	Package	Weight	Base qty	Delivery mode
X00605MA 1AA2	X0605MA	TO-92	0.2g.	2500	Bulk

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